United States Patent [19]

Kaise et al.

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[54] **CIRCUIT TESTER**

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[**] Term: 14 Years

[21] Appl. No.: **29/093,423**

[56]

FIG. 2 is a perspective view thereof with the cover thereof closed;

FIG. 3 is a perspective view thereof with the test leads thereof pulled out;

FIG. 4 is a front elevational view thereof;

FIG. 5 is a rear elevational view thereof;

FIG. 6 is a top plan view thereof;

FIG. 7 is a bottom plan view thereof;

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[52] U.S. Cl. D10/78
[58] Field of Search D10/78; 324/154 PB,

324/158.1, 751, 752

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[57] CLAIM

The ornamental design for a circuit tester, as shown and described.

FIG. 8 is a left side elevational view thereof;

FIG. 9 is a right side elevational view thereof;

FIG. 10 is a front elevational view thereof with the cover thereof closed;

FIG. 11 is a rear elevational view thereof with the cover thereof closed;

FIG. 12 is a top plan view thereof with the cover thereof closed;

FIG. 13 is a bottom plan view thereof with the cover thereof closed;

FIG. 14 is a left side elevational view thereof with the cover thereof closed;

FIG. 15 is a right side elevational view thereof with the cover thereof closed;

FIG. 16 is a front elevational view thereof in which the cover is turned until reaching a rear face of a body proper; and,

FIG. 17 is a bottom plan view thereof in which the cover is

turned until reaching the rear face of the body proper.

DESCRIPTION

FIG. 1 is a perspective view of a circuit tester showing my new design;

1 Claim, 6 Drawing Sheets



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FIG.5



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FIG.6



FIG.7



FIG.8 FIG.9





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FIG.13



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FIG.16



FIG.17
